

Search Notes

Application/Control No.

10/706,902

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

CHAE ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	66	7/6/2006	BT
216	72	7/6/2006	BT
216	74	7/6/2006	BT
438	725	7/6/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	7/6/2006	BT